

Fig. S1. Wide XPS scan of sample #1 (cut from pristine T-tube)

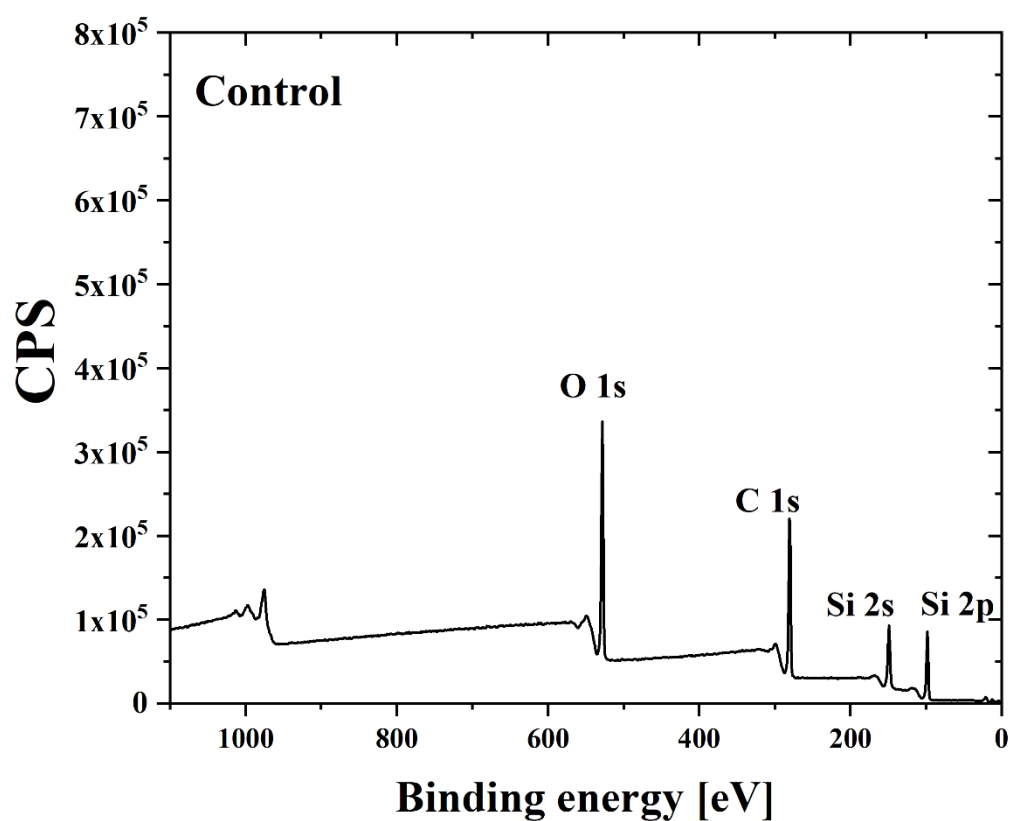


Fig. S2. Wide XPS scan of sample #3 (cut from plasma-treated T-tube)

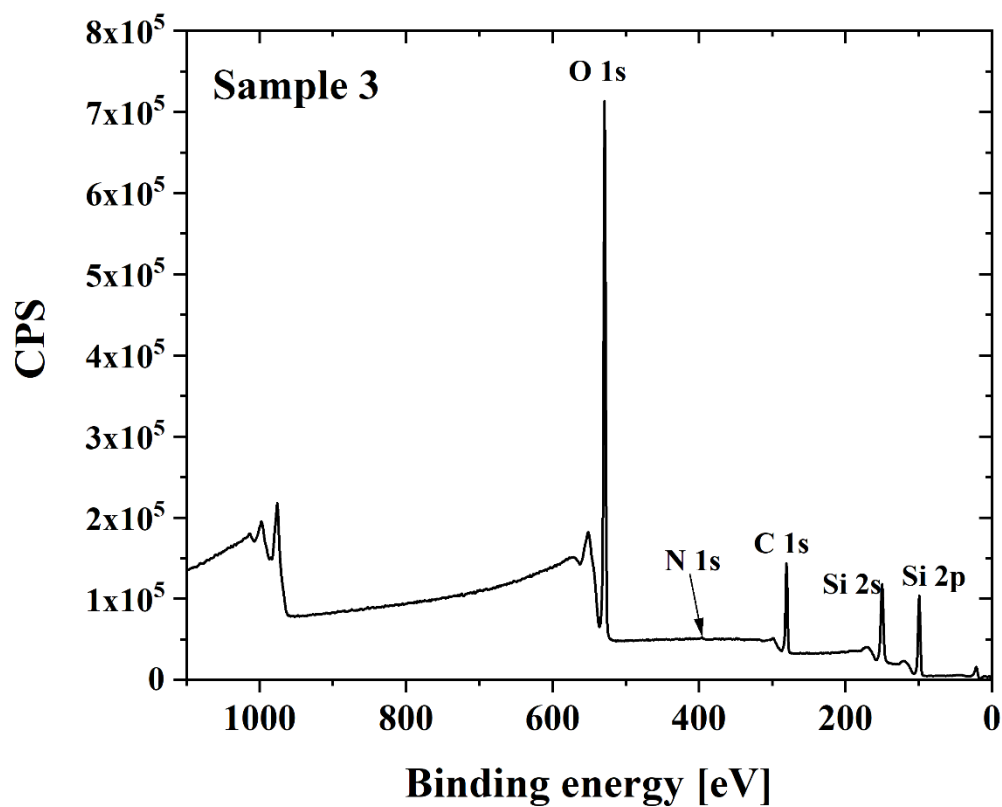


Fig. S3. High-resolution XPS scan of Si2p peak of sample #1 (pristine T-tube)

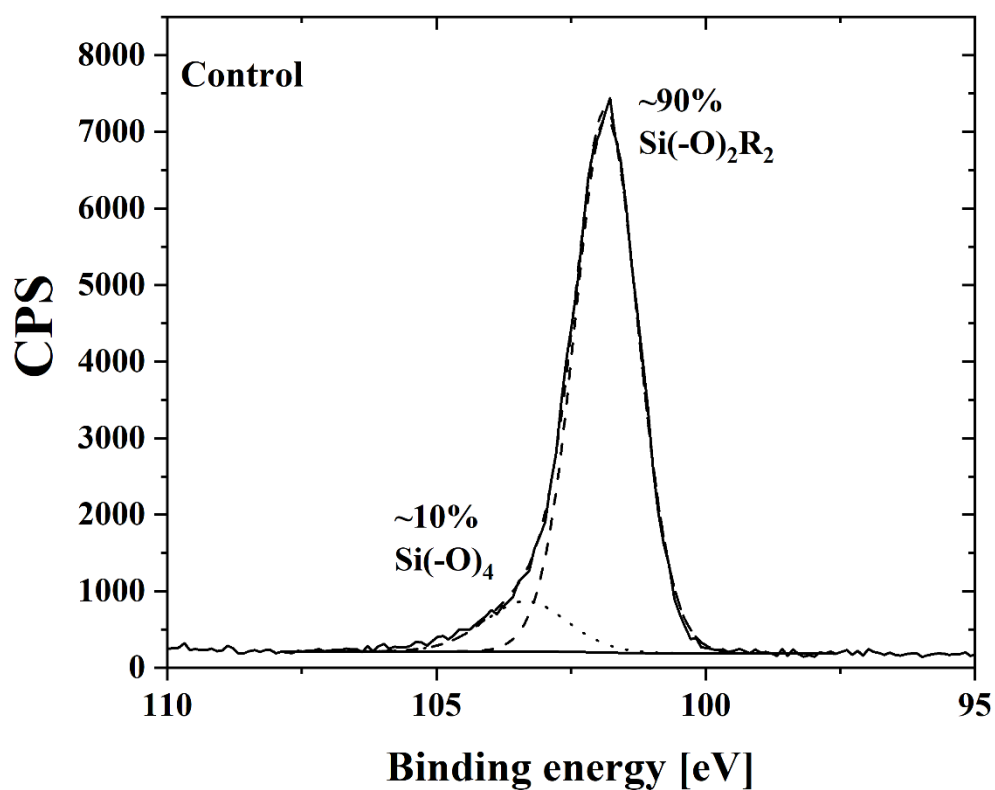


Fig. S4. High-resolution XPS scan of Si2p peak of sample #3 (treated T-tube)

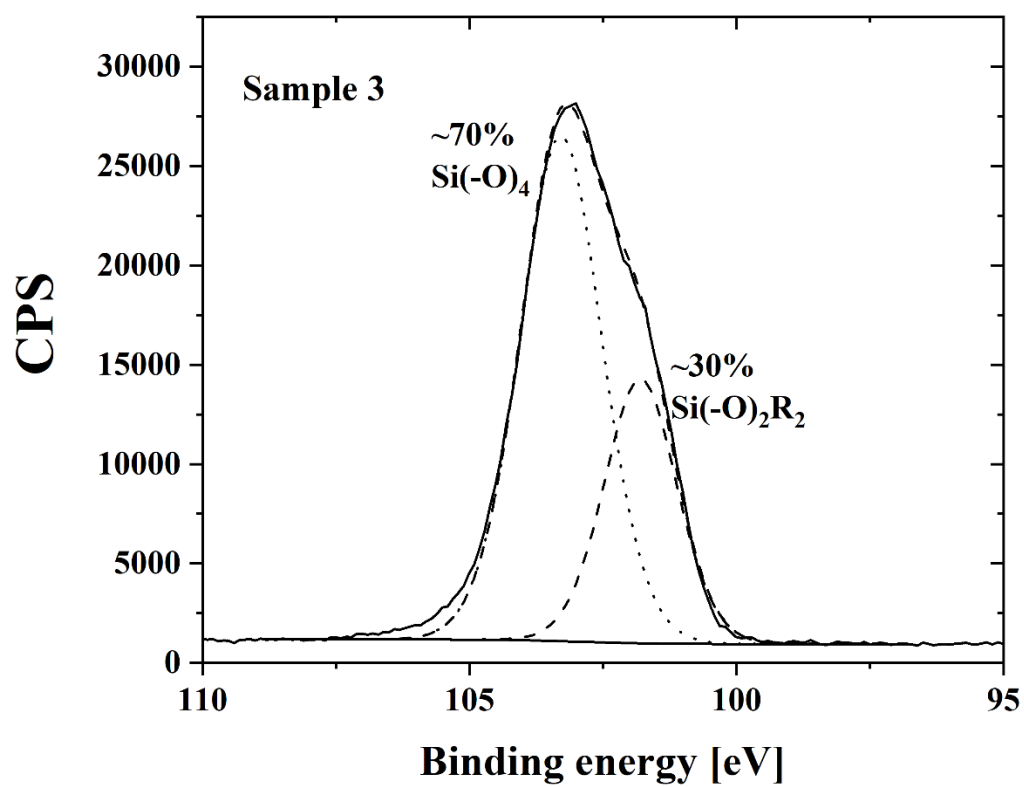
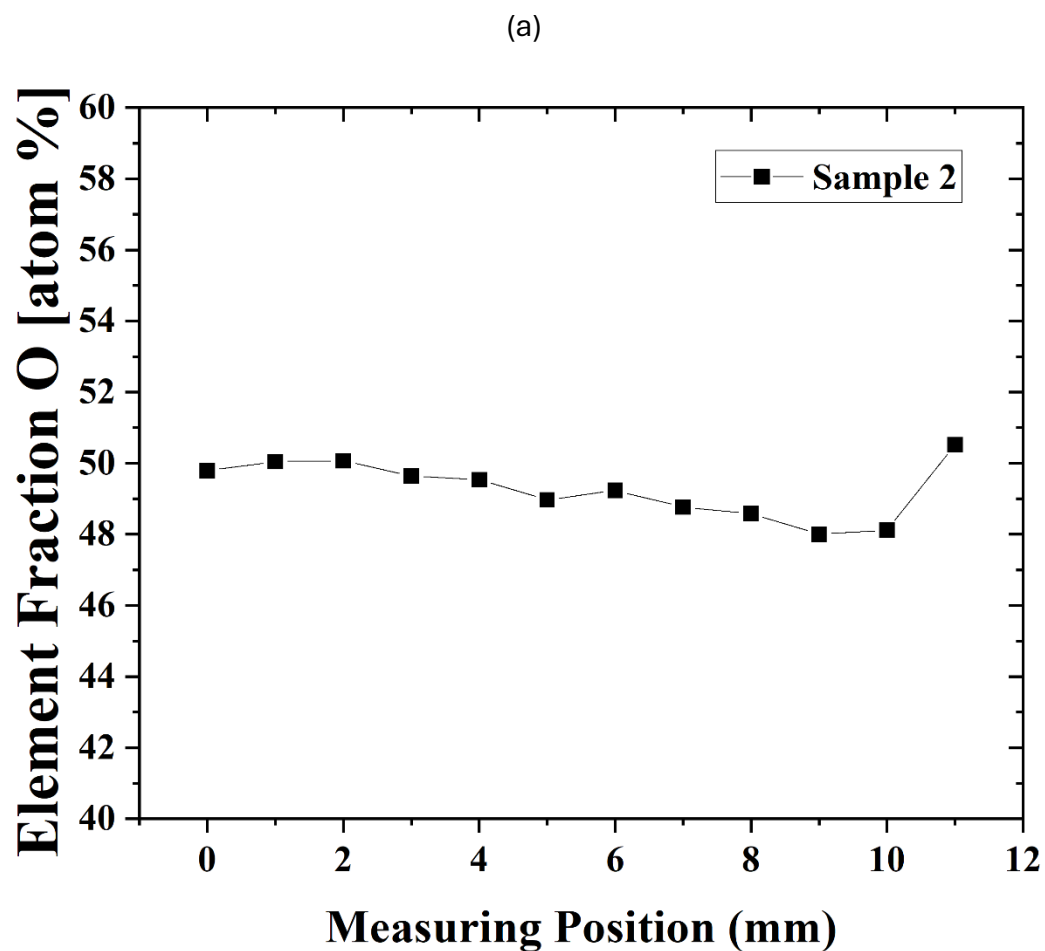
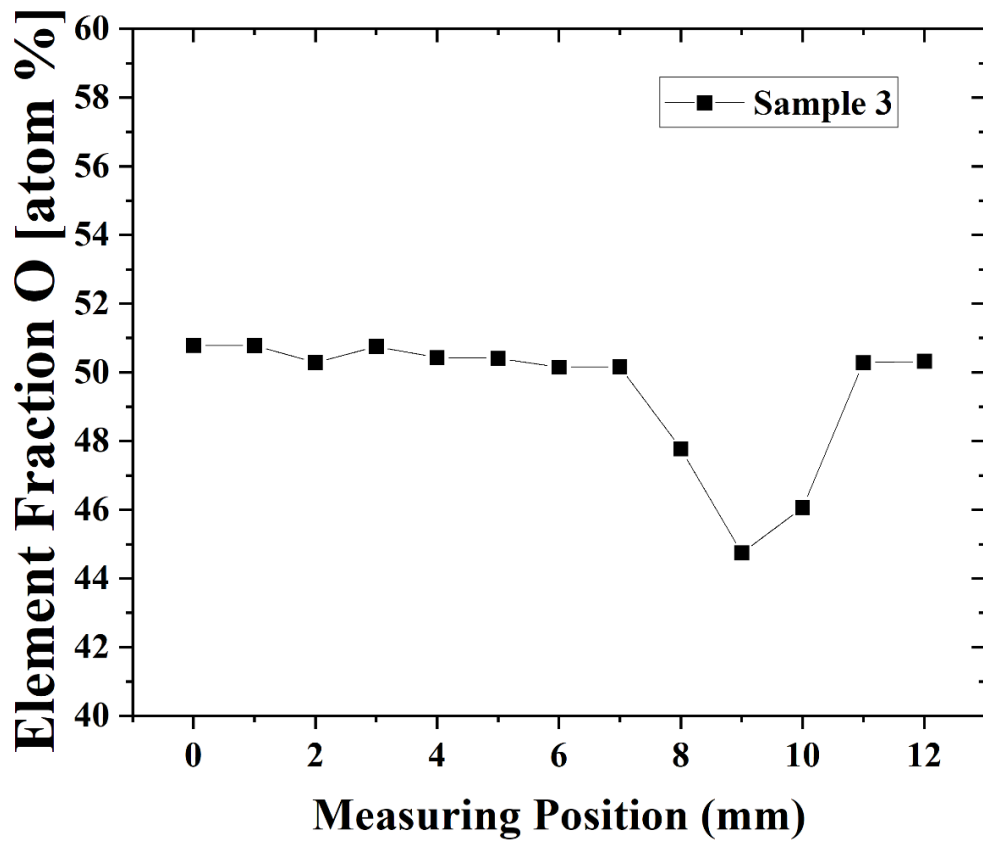


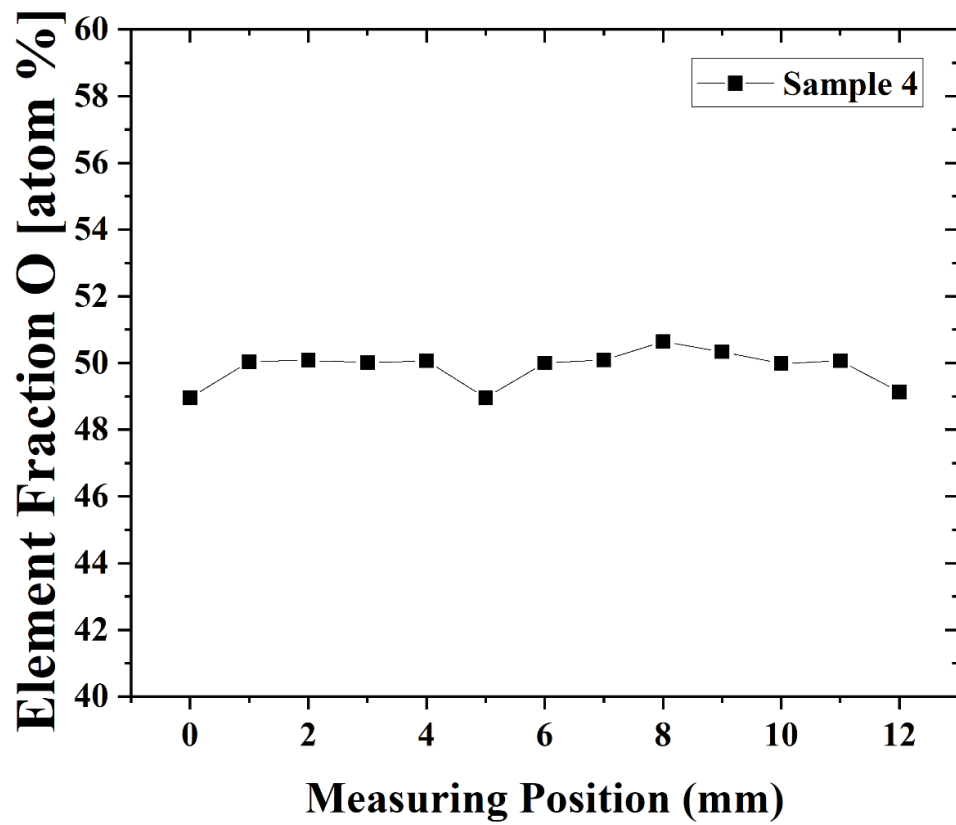
Fig. S5 (a-g). Detailed view of the O content of plasma-treated samples (2-8) measured by XPS. The scan was made along the longitudinal sample dimension with resolution of 1 mm.



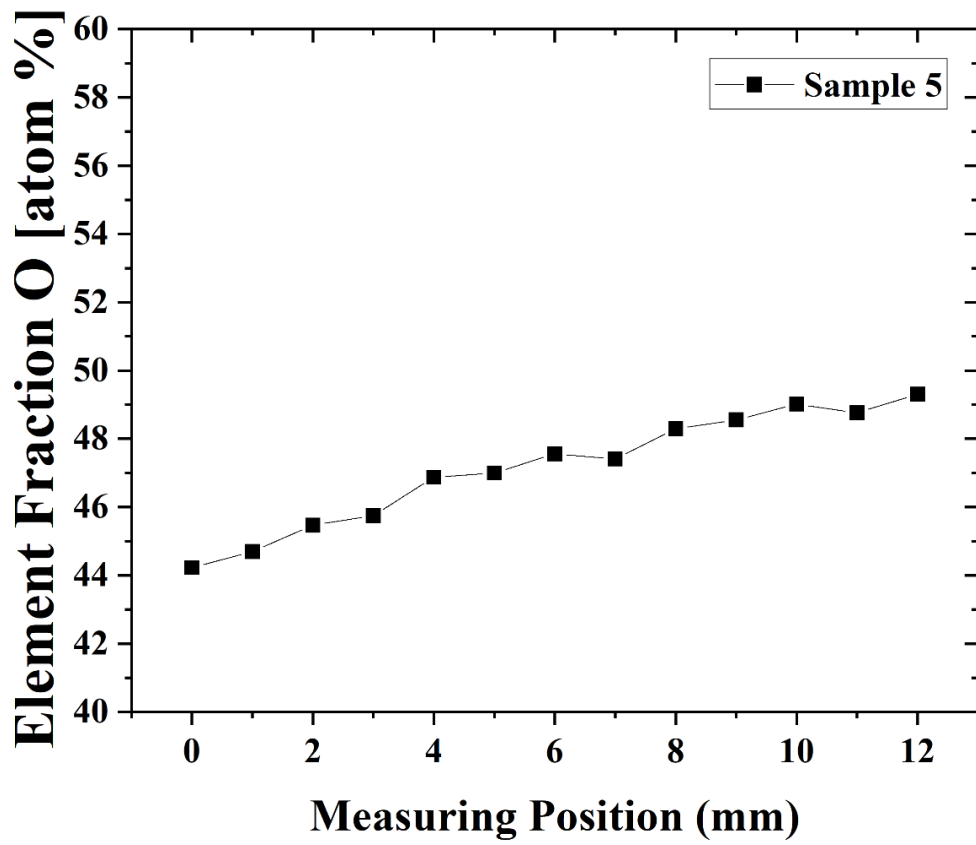
(b)



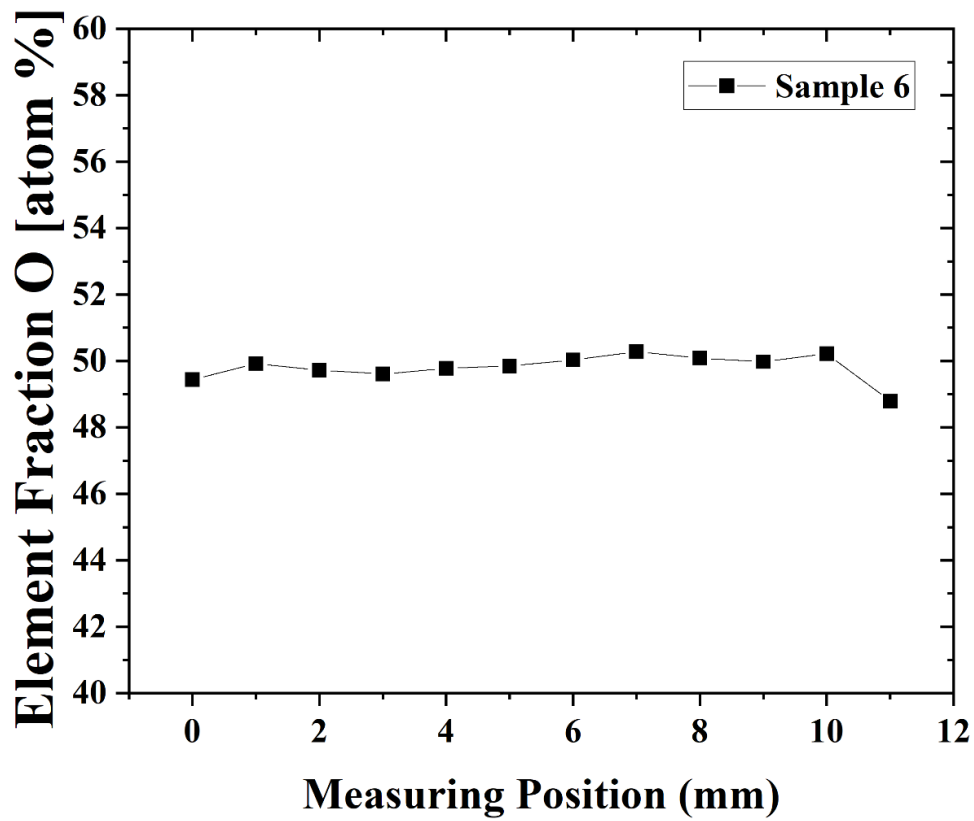
(c)



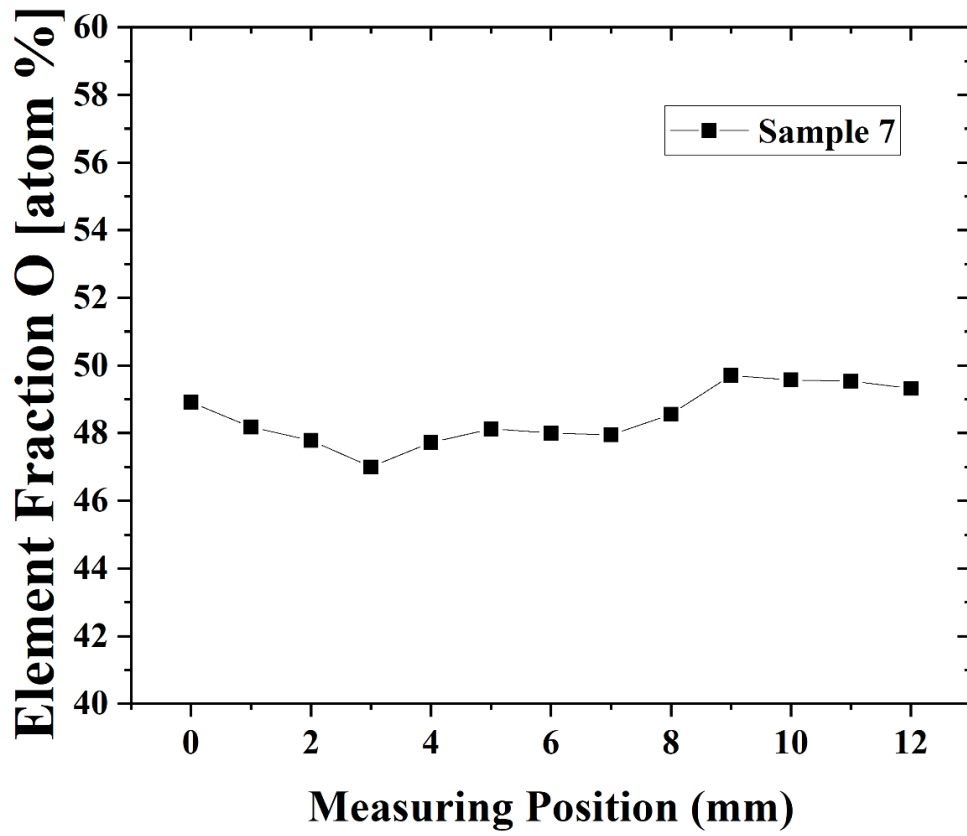
(d)



(e)



(f)



(g)

